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Sue Bromaghin

March 30, 2006

CUSTOMER NO. 36257

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Ibrahim ABDULHALIM et al.

Title: Periodic Patterns and Technique to Control
Misalignment Between Two Layers

Application No.: 10/699,153

Filing Date: October 30, 2003

Examiner: Layla G. LAUCHMAN

Group Art Unit: 2877

Docket No.: TNCR.196US2

Conf. No.: 1463

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

☒ According to 37 C.F.R. 1.98(2)(ii), copies of the U.S. Patents and U.S. Published Patent Applications documents are not required and are therefore not enclosed. Copies of the listed foreign patent documents or Other Art are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a

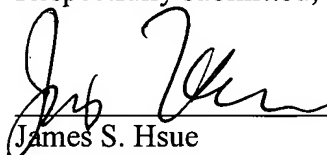
Attorney Docket No.: TNCR.196US2

Application No.: 10/699,153

representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee is believed to be due. The Commissioner is authorized, however, to charge any fee that may be required against Deposit Account No. 502664. This form is being submitted in duplicate.

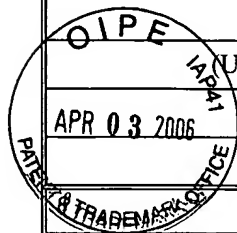
Respectfully submitted,


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March 30, 2006
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| U.S. Department of Commerce, Patent and Trademark | Atty. Docket No. | Application No. |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT | TNCR.196US2 | 10/699,153 |
| | Applicant(s) | Conf. No. |
| (Use several sheets if necessary) | Ibrahim ABDULHALIM et al. | 1463 |
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Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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